

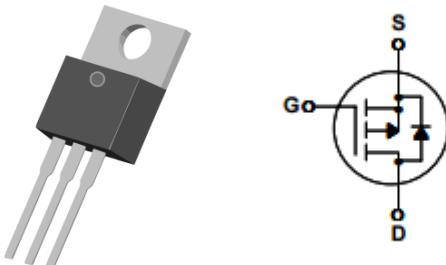
Description

This P-channel MOSFETS use advanced trench technology and design to provide excellent RDS(on) with low gate charge. It can be used in a wide variety of applications.

Features

BVDSS	RDS(on)	ID
-60V	0.14Ω	-18A

- 1) Low gate charge.
- 2) Green device available.
- 3) Advanced high cell density trench technology for ultra RDS(ON)
- 4) Excellent package for good heat dissipation.



TO-220

Absolute Maximum Ratings $T_c=25^\circ\text{C}$,unless otherwise noted

Symbol	Parameter	Ratings	Units
VDS	Drain-Source Voltage	-60	V
VGS	Gate-Source Voltage	± 20	V
ID	Continuous Drain Current-1	-18	A
	Continuous Drain Current-T=100°C	-13	
	Pulsed Drain Current2	-72	
EAS	Single Pulse Avalanche Energy3	370	mJ
PD	Power Dissipation4	88	W
TJ, TSTG	Operating and Storage Junction Temperature Range	-55 to +175	°C

Thermal Characteristics

KERSMI ELECTRONIC CO.,LTD.
-60V P-channel MOSFET

Symbol	Parameter	Ratings	Units
R_{JC}	Thermal Resistance ,Junction to Case1	62	$^{\circ}\text{C}/\text{W}$
R_{JA}	Thermal Resistance, Junction to Ambient1	1.7	

Package Marking and Ordering Information

Part NO.	Marking	Package
KSM9Z34	KSM9Z34	TO-220

Electrical Characteristics $T_c=25^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Conditions	Min	Typ	Max	Units
Off Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{DS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	-60	—	—	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=0\text{V}, V_{\text{GS}}=32\text{V}$	—	—	-100	μA
I_{GSS}	Gate-Source Leakage Current	$V_{\text{DS}}=\pm 20\text{V}, V_{\text{GS}}=0\text{A}$	—	—	± 100	nA
On Characteristics						
$V_{\text{GS}(\text{th})}$	GATE-Source Threshold Voltage	$V_{\text{DS}}=V_{\text{DS}}, I_{\text{D}}=250\mu\text{A}$	-2.0	—	-4.0	V
$R_{\text{DS}(\text{ON})}$	Drain-Source On Resistance ²	$V_{\text{DS}}=10\text{V}, I_{\text{D}}=6\text{A}$	—	—	0.14	Ω
		$V_{\text{DS}}=2.5\text{V}, I_{\text{D}}=5\text{A}$	—	—	—	---
G_{FS}	Forward Transconductance	$V_{\text{DS}}=5\text{V}, I_{\text{D}}=12\text{A}$	5.9	—	—	S
Dynamic Characteristics						
C_{iss}	Input Capacitance	$V_{\text{DS}}=15\text{V}, V_{\text{GS}}=0\text{V}, f=1\text{MHz}$	—	1100	—	pF
C_{oss}	Output Capacitance		—	620	—	
C_{rss}	Reverse Transfer Capacitance		—	100	—	
Switching Characteristics						
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	$V_{\text{DS}}=20\text{V}, V_{\text{GS}}=10\text{V}, R_{\text{GEN}}=3.3\Omega$	—	18	—	ns
t_{r}	Rise Time		—	120	—	ns
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time		—	20	—	ns
t_{f}	Fall Time		—	58	—	ns
Q_{g}	Total Gate Charge	$V_{\text{GS}}=4.5\text{V}, V_{\text{DS}}=20\text{V}, I_{\text{D}}=6\text{A}$	—	—	34	nC
Q_{gs}	Gate-Source Charge		—	—	9.9	nC
Q_{gd}	Gate-Drain "Miller" Charge		—	—	16	nC
Drain-Source Diode Characteristics						
V_{SD}	Source-Drain Diode ForwardVoltage ²	$V_{\text{GS}}=0\text{V}, I_{\text{S}}=1\text{A}$	—	—	-6.3	V
t_{rr}	Reverse Recovery Time	$I_{\text{F}}=7\text{A}, dI/dt=100\text{A}/\mu\text{s}$	—	100	200	ns
Q_{rr}	Reverse Recovery Charge		—	0.28	0.52	nC

Notes:

1. The data tested by surface mounted on a 1 inch² FR-4 board 2OZ copper.
2. The data tested by pulse width≤300us,duty cycle≤2%
3. The EAS data shows Max.rating.The test condition is $V_{DD}=25V, V_{GS}=10V, L=0.1mH, i_{AS}=17.8A$
4. The power dissipation is limited by 150°C junction temperature.

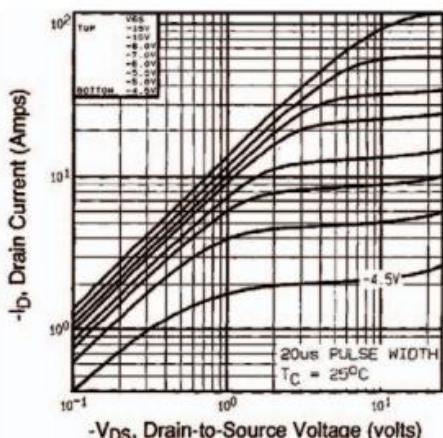
Typical Characteristics $T_J=25^{\circ}\text{C}$ unless otherwise noted


Fig. 1 Typical Output Characteristics,
 $T_C = 25^{\circ}\text{C}$

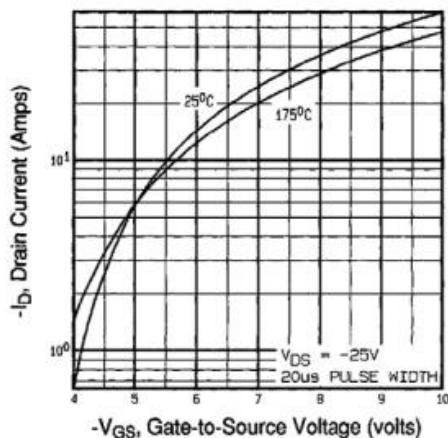


Fig. 2 Typical Transfer Characteristics

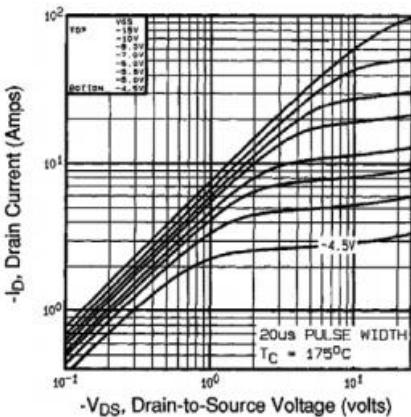


Fig. 3 Typical Output Characteristics,
 $T_C = 150^{\circ}\text{C}$

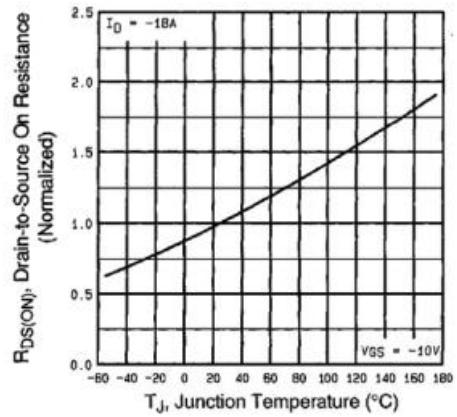
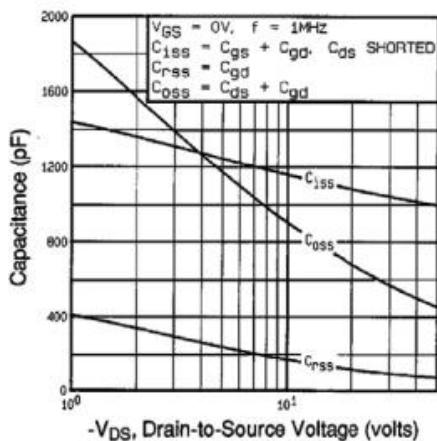
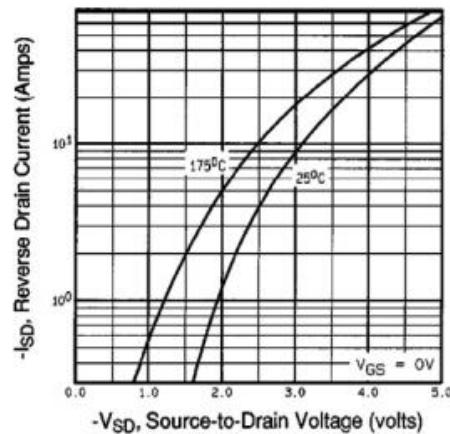


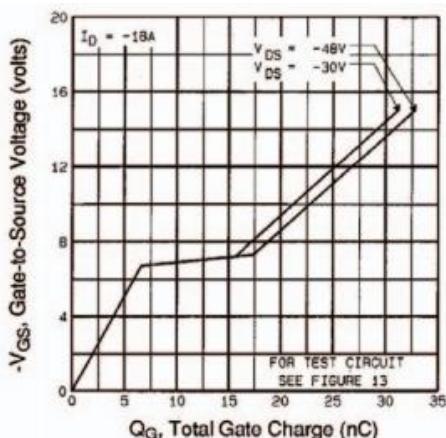
Fig. 4 - Normalized On-Resistance vs.
Temperature

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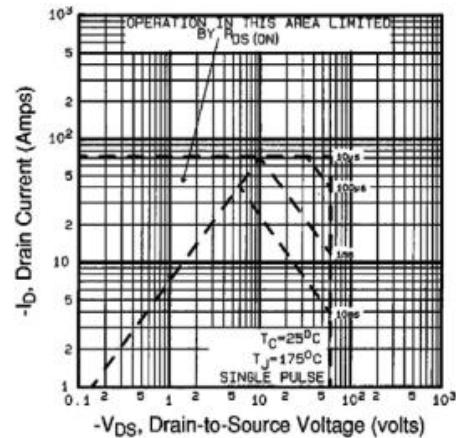
**Fig. 5 - Typical Capacitance vs.
Drain-to-Source Voltage**



**Fig. 6 - Typical Source-Drain
Diode Forward Voltage**



**Fig. 7 - Typical Gate Charge vs.
Gate-to-Source Voltage**



**Fig. 8 - Maximum Safe
Operating Area**

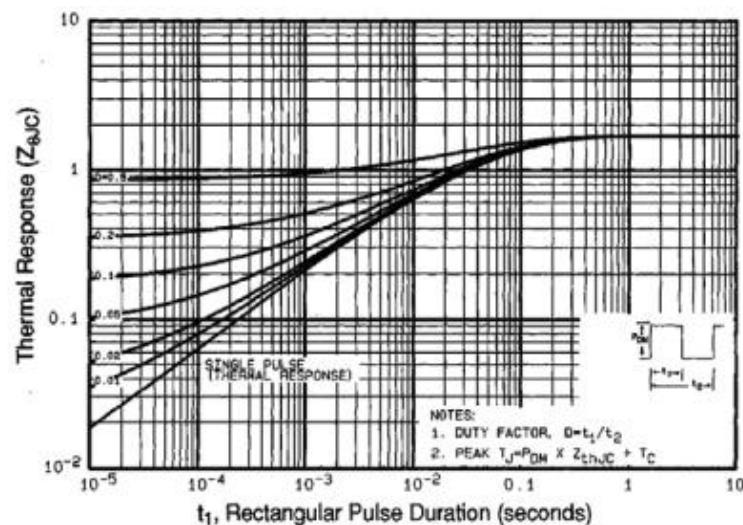


Fig. 9 - Maximum Effective Transient Thermal Impedance, Junction-to-Case